

# MOS FIELD EFFECT TRANSISTOR

2SK3357

# SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

#### **DESCRIPTION**

The 2SK3357 is N-channel MOS Field Effect Transistor designed for high current switching applications.

# ORDERING INFORMATION

PART NUMBER	PACKAGE		
2SK3357	TO-3P		

## **FEATURES**

• Super low on-state resistance:

 $R_{\text{DS(on)1}} = 5.8 \, m\Omega$  MAX. (Vgs = 10 V, Ip = 38 A)

 $R_{DS(on)2} = 8.8 \text{ m}\Omega$  MAX. (Vgs = 4.0 V, ID = 38 A)

- Low Ciss: Ciss = 9800 pF TYP.
- Built-in gate protection diode

(TO-3P)



# ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage	Voss	60	V
Gate to Source Voltage	$V_{\text{GSS(AC)}}$	±20	V
Drain Current (DC)	I <sub>D(DC)</sub>	±75	Α
Drain Current (pulse) Note1	I <sub>D(pulse)</sub>	±300	Α
Total Power Dissipation (Tc = 25°C)	$\mathbf{P}_{T}$	150	W
Total Power Dissipation (T <sub>A</sub> = 25°C)	$\mathbf{P}_{T}$	3.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	T <sub>stg</sub>	-55 to +150	°C
Single Avalanche Current Note2	IAS	75	Α
Single Avalanche Energy Note2	Eas	562	mJ

**Notes 1.** PW  $\leq$  10  $\mu$ s, Duty cycle  $\leq$  1 %

**2.** Starting T<sub>ch</sub> = 25°C, R<sub>G</sub> = 25  $\Omega$ , V<sub>GS</sub> = 20 V  $\rightarrow$  0 V

## THERMAL RESISTANCE

Channel to Case	Rth(ch-C)	0.83	°C/W	
Channel to Ambient	Rth(ch-A)	41.7	°C/W	

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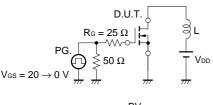
Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

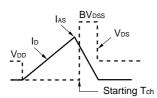


# ELECTRICAL CHARACTERISTICS (TA = 25 °C)

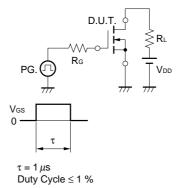
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CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	RDS(on)1	Vgs = 10 V, ID = 38 A		4.6	5.8	mΩ
	RDS(on)2	Vgs = 4.0 V, ID = 38 A		6.1	8.8	mΩ
Gate to Source Cut-off Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance	<b>y</b> fs	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 38 A	38	72		S
Drain Leakage Current	IDSS	Vps = 60 V, Vgs = 0 V			10	μΑ
Gate to Source Leakage Current	Igss	Vgs = ±20 V, Vps = 0 V			±10	μΑ
Input Capacitance	Ciss	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz		9800		pF
Output Capacitance	Coss			1500		pF
Reverse Transfer Capacitance	Crss			630		pF
Turn-on Delay Time	td(on)	$I_D = 38 \text{ A}, V_{GS(on)} = 10 \text{ V}, V_{DD} = 30 \text{ V},$		105		ns
Rise Time	<b>t</b> r	$R_G = 10 \Omega$		1350		ns
Turn-off Delay Time	td(off)			500		ns
Fall Time	<b>t</b> f			480		ns
Total Gate Charge	Q <sub>G</sub>	ID = 75 A , VDD = 48 V, VGS = 10 V		170		nC
Gate to Source Charge	Qgs			28		nC
Gate to Drain Charge	Q <sub>GD</sub>			46		nC
Body Diode Forward Voltage	V <sub>F(S-D)</sub>	IF = 75 A, VGS = 0 V		0.96		V
Reverse Recovery Time	trr	IF = 75 A, VGS = 0 V,		64		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		130		nC

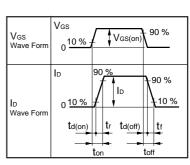
# **TEST CIRCUIT 1 AVALANCHE CAPABILITY**



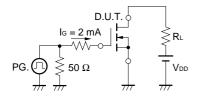


# TEST CIRCUIT 2 SWITCHING TIME



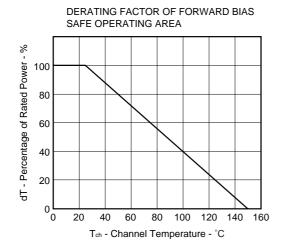


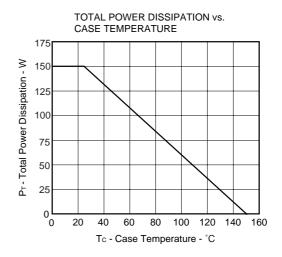
# **TEST CIRCUIT 3 GATE CHARGE**

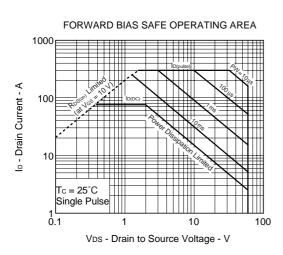




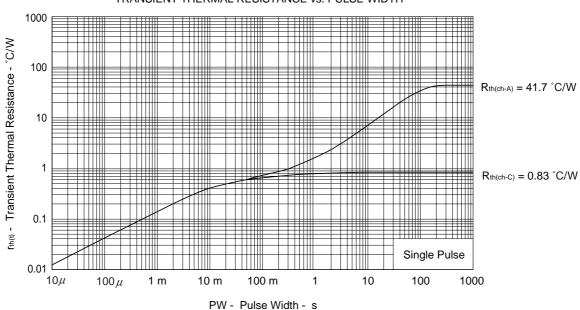
# **★ TYPICAL CHARACTERISTICS (TA = 25 °C)**







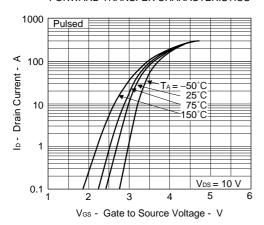
# TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



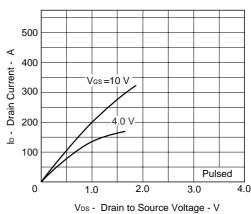
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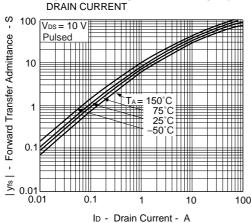
#### FORWARD TRANSFER CHARACTERISTICS



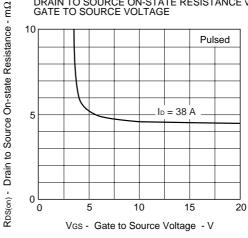
# DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



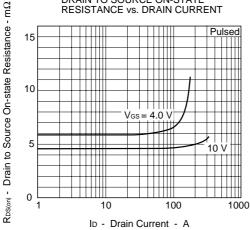
FORWARD TRANSFER ADMITTANCE vs.



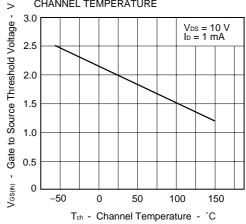
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



DRAIN TO SOURCE ON-STATE

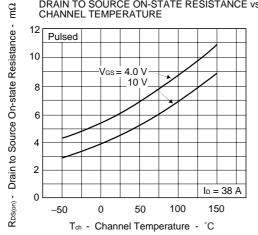


GATE TO SOURCE THRESHOLD VOLTAGE vs. CHANNEL TEMPERATURE

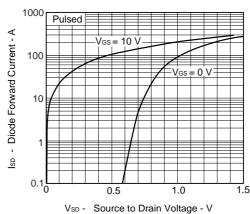




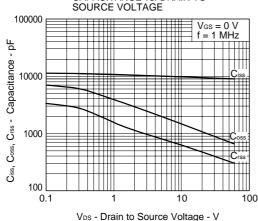
# DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



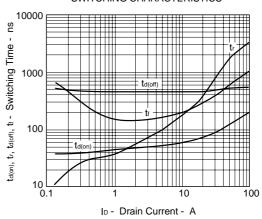
#### SOURCE TO DRAIN DIODE FORWARD VOLTAGE



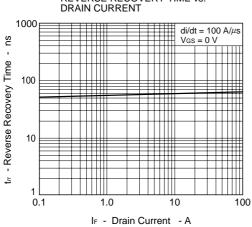
# CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



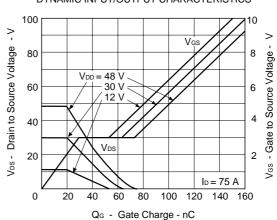
## SWITCHING CHARACTERISTICS

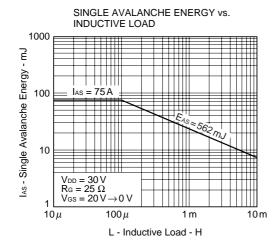


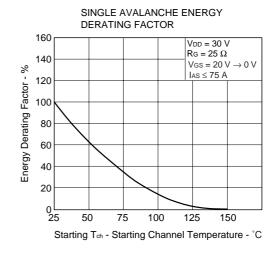
# REVERSE RECOVERY TIME vs. DRAIN CURRENT



# DYNAMIC INPUT/OUTPUT CHARACTERISTICS



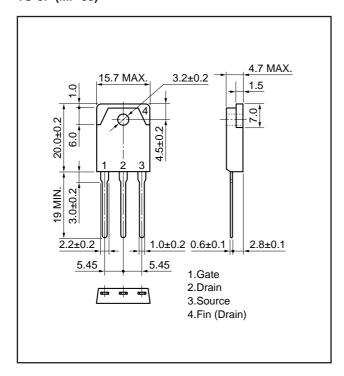




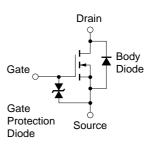


# PACKAGE DRAWING (Unit: mm)

# TO-3P (MP-88)



## **EQUIVALENT CIRCUIT**



**Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

7

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